

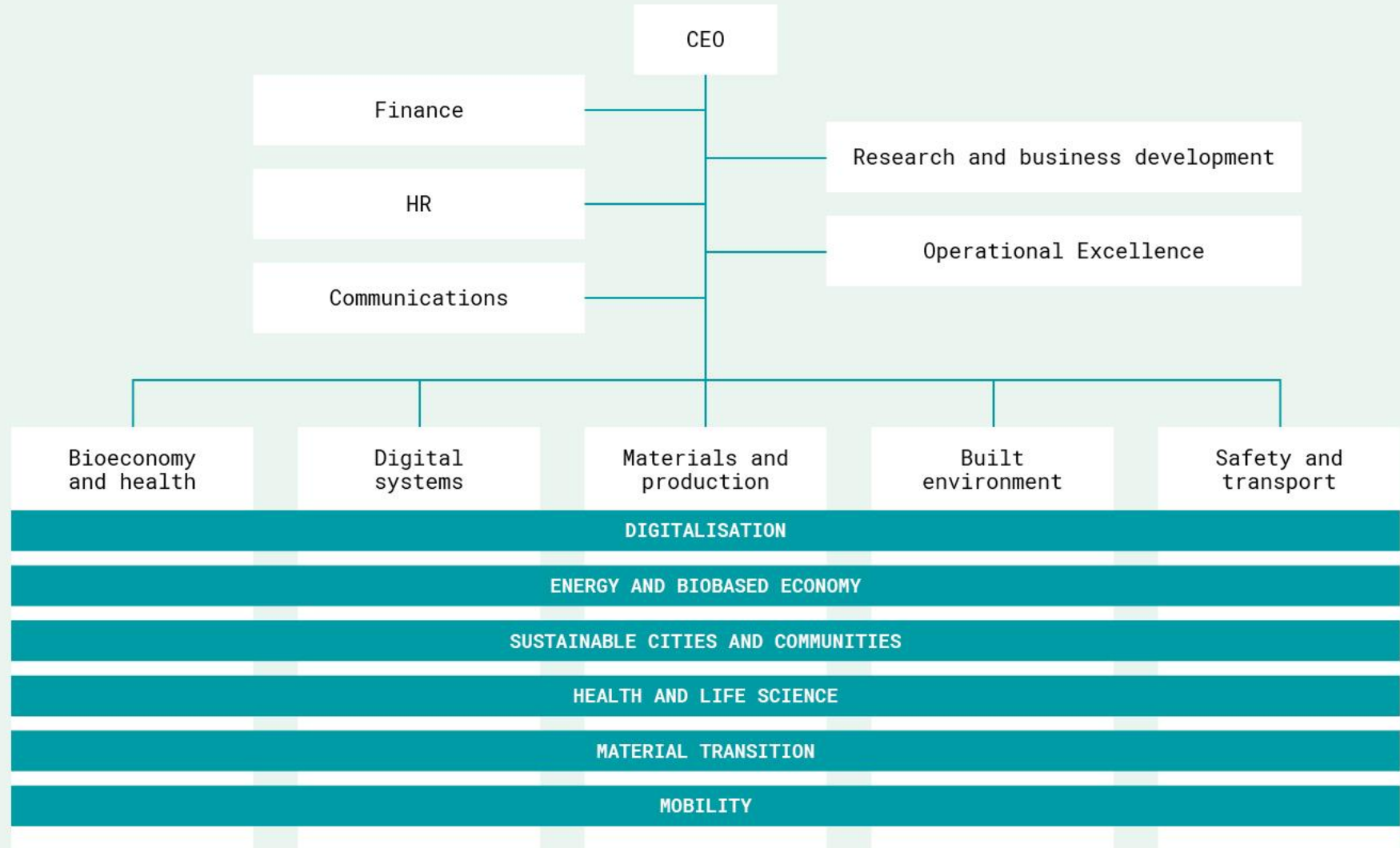


RI.
SE

RESEARCH INSTITUTES OF SWEDEN

**The Swedish research
institution and innovation
partner for every part
of society**

RISE today



RISE Smart Hardware

120 employees

5 adjunct professors

~ 18MEUR turnover

7 Business Units

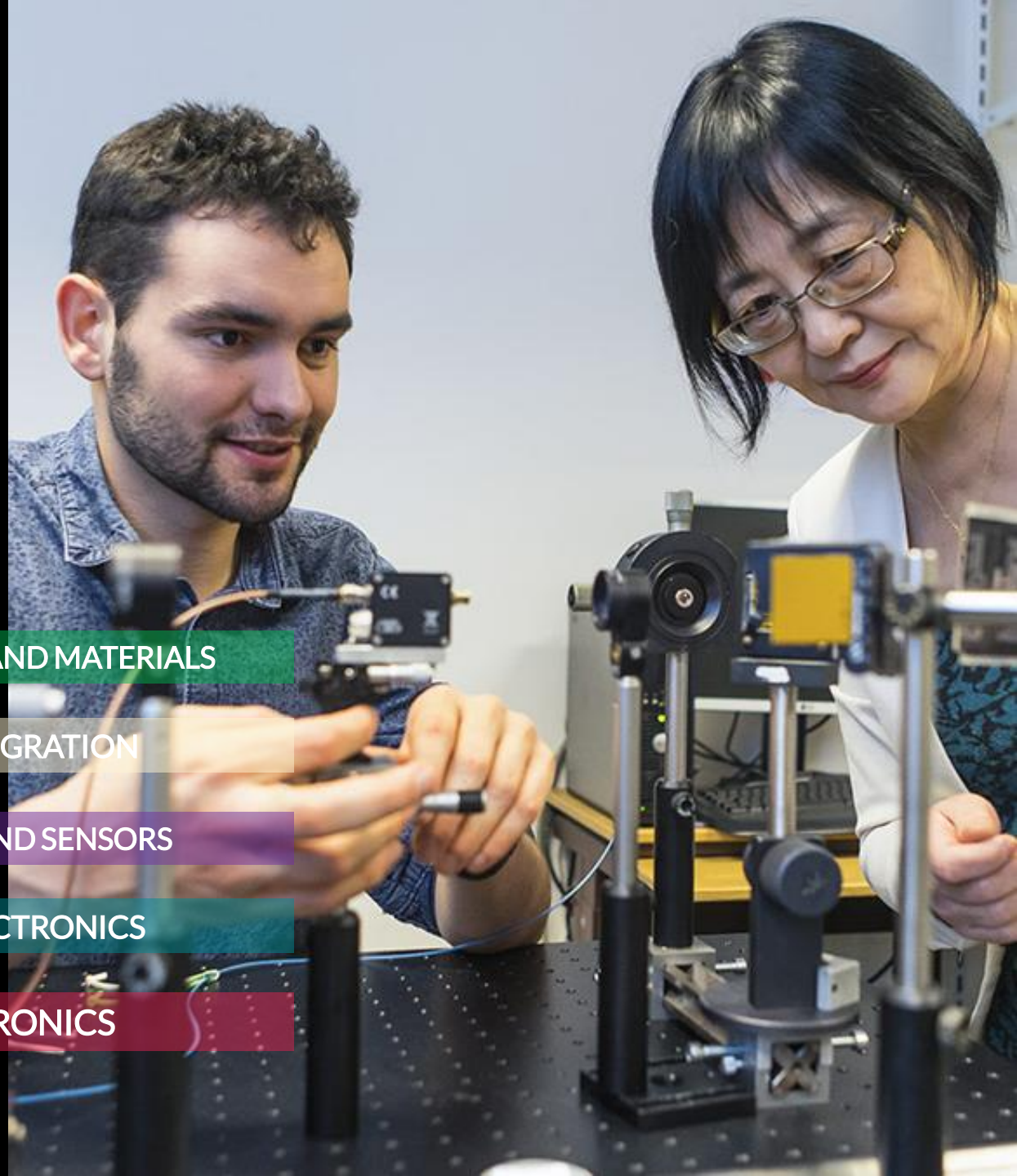
SENSOR SYSTEMS AND MATERIALS

SYSTEM INTEGRATION

FIBER OPTICS AND SENSORS

PRINTED ELECTRONICS

BIOELECTRONICS



Test & demo facilities



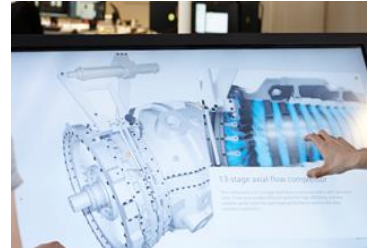
ProNano



Electrum Laboratory



Fiberlab



Visualization Table



UAV



DigiCore



**Applied Laboratory for
Digital Transformation**



The Pink



**Printed Electronics
Arena 4.0**



**Autonomous shared
transport**



Urban ICT Arena



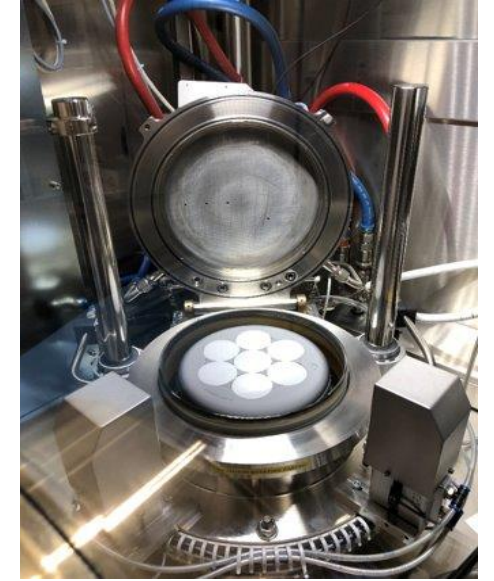
**ICE - Infrastructure and
Cloud Environment**

Nano Technology Unit at RISE

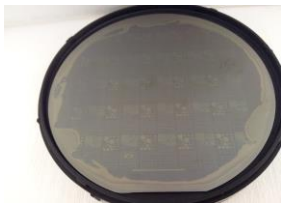
- ProNano T&D lab and Electrum for scale-up
- MOCVD processing of material for GaN/AlGaN-based electronic and optical devices
- Hetero-structures of III-N and other wide bandgap materials, SiC, Ga₂O₃ as well as 2D materials such as graphene
- Electronic/photonic devices and systems based on semiconductor materials including GaN, SiC, Ga₂O₃,
- AlGaN/GaN based High-Electron-Mobility Transistor (HEMT) for Power Electronic and RF Applications



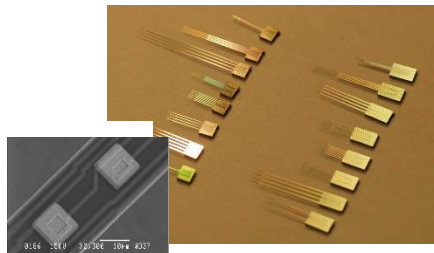
ISO-9001 certificated clean-room facilities and various characterization tools/setups at Kista and Lund



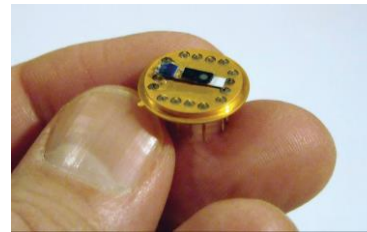
Aixtron Flip Top CCS G-III-Nitride MOCVD System



Wafer-scale component design and fabrication



Si based micro needles



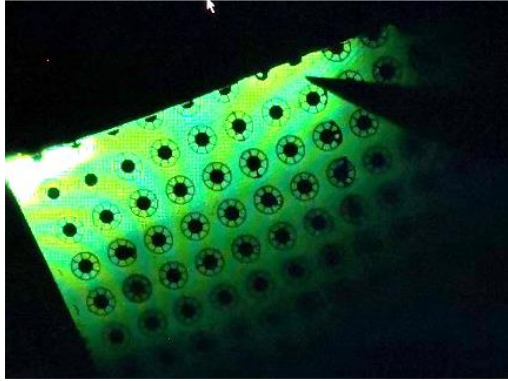
SiC MESFET Gas sensors



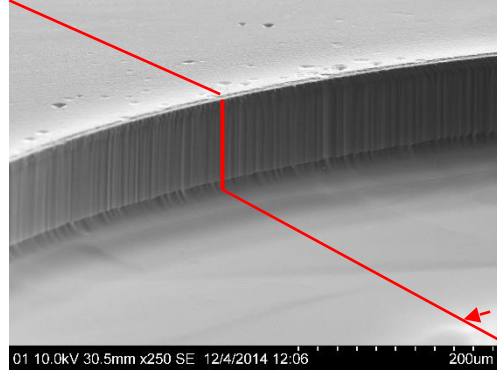
SiC based all-optical high-pressure (350 bar) and high-temperature (1000 °C) sensors for automotive industry and space applications



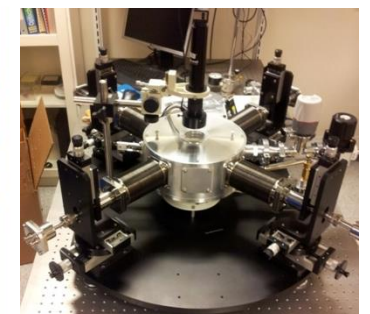
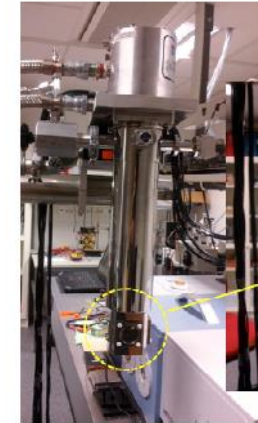
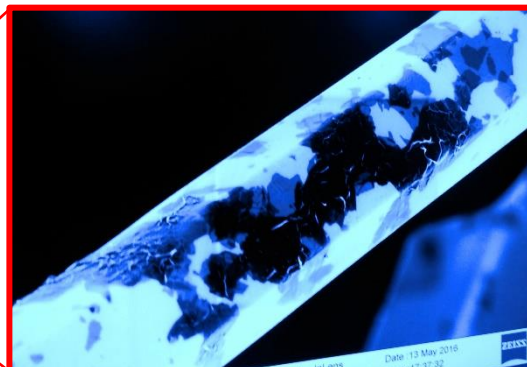
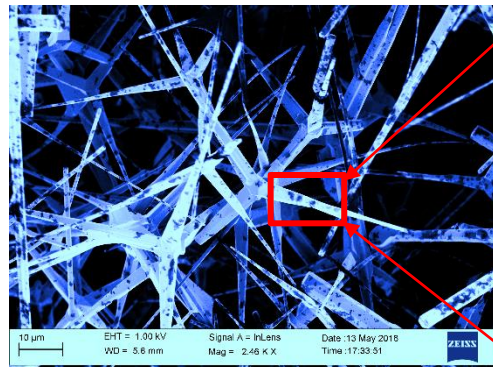
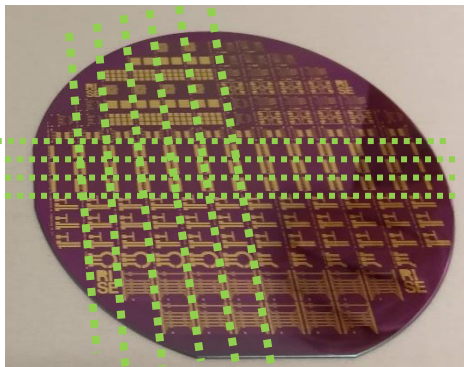
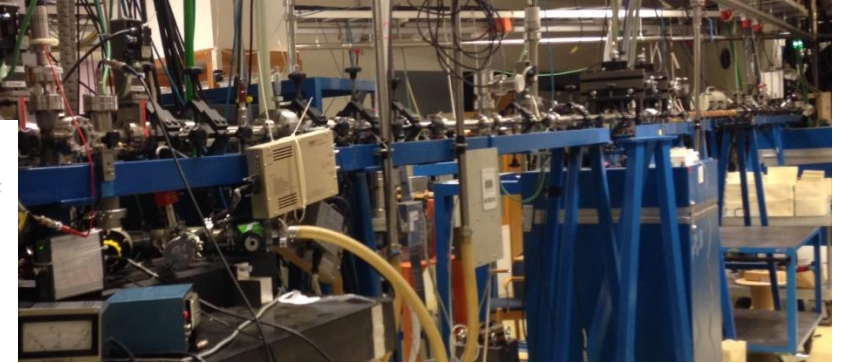
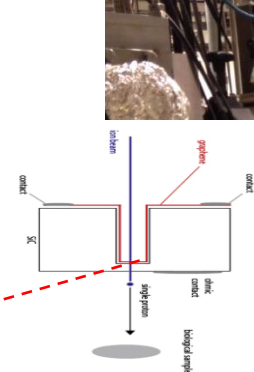
Nano Technology Unit at RISE



CVD graphene as transparent electrode to operate green LED array

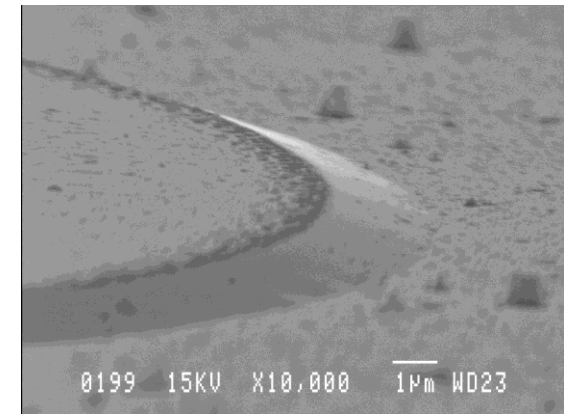
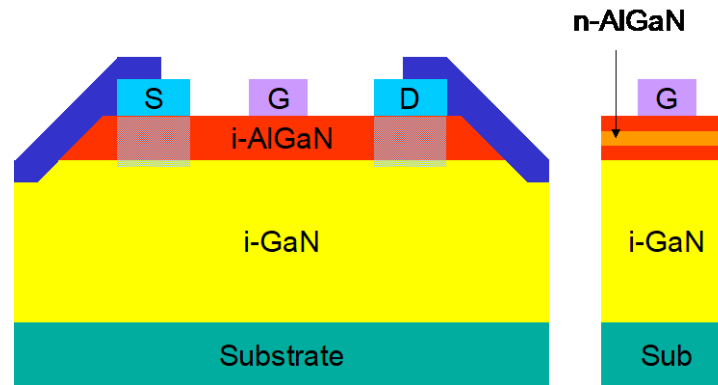
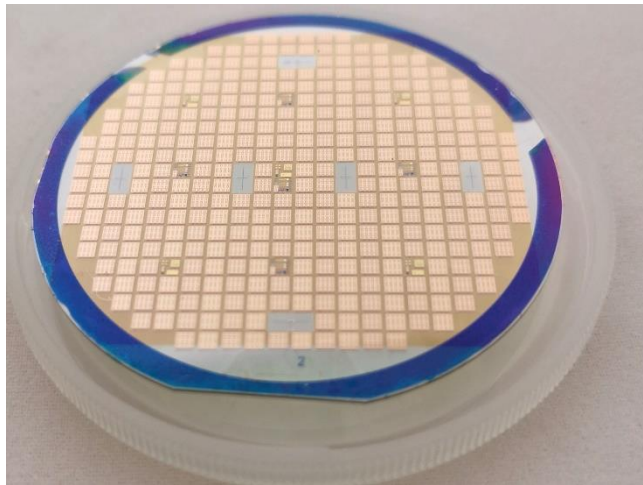
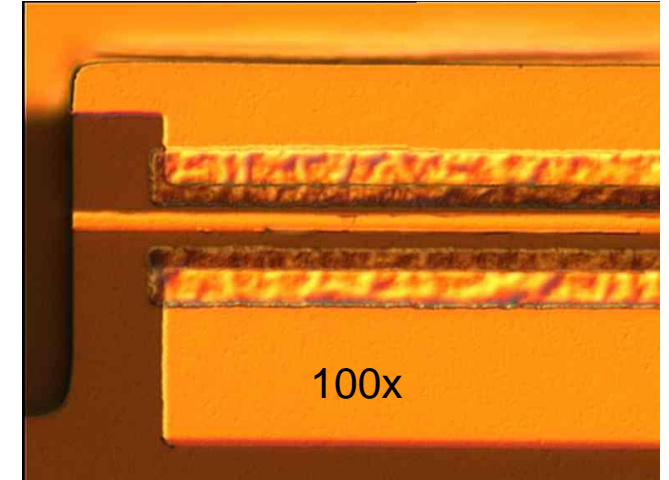
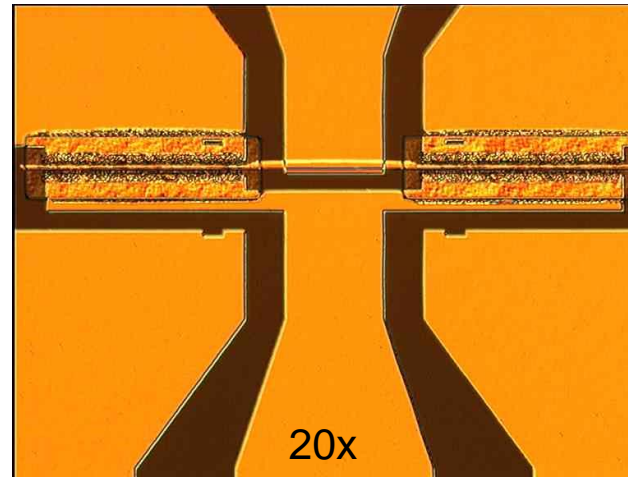
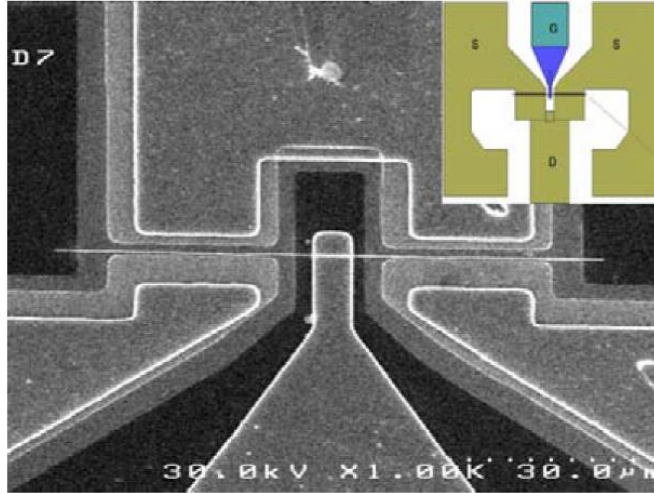


3D graphene on SiC membrane as thin ion transmission detectors that applied in accelerator based systems to study the influence of low-dose particle radiation on living cells



Bio/chemical sensors using large area graphene or graphene/ZnO hybrids for forensic and MedTech applications

GaN based HEMTs Design, Fabrication & Test

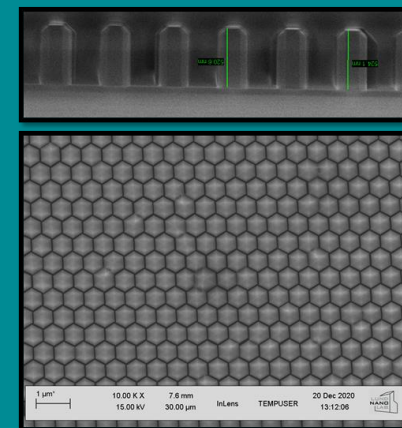


EU DENIS project: Development of low dislocation density Gallium Nitride substrates

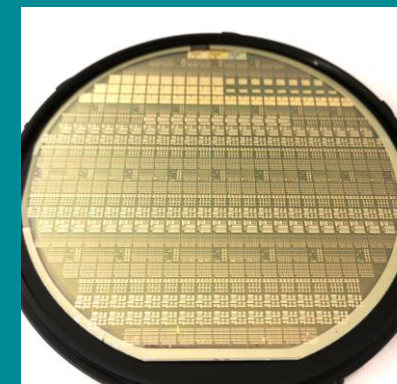
UltimateGaN: Coupling ProNano/Electrum to the European Ecosystem for next generation nanomaterial for Power Electronics

UltimateGaN – Research for GaN technologies, devices and applications to address the challenges of the future GaN roadmap

- Project partners: 26 partners from 9 countries
- Project start: May 2019 for a duration of 3 years
- Total costs: ~ EUR 48 Mio. incl. ~3800 person months
- Full value chain addressed by collaboration of partners from regions all over Europe in the work packages



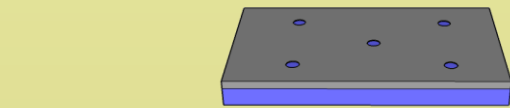
GaN nanowires from RISE ProNano ToD



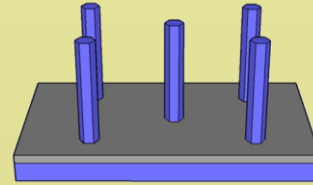
GaN HEMT Power Transistors from RISE Electrum ToD

Novel Nanowire based GaN Epitaxy– UltimateGaN

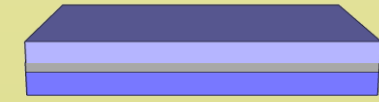
Unique GaN epitaxy on Silicon wafers



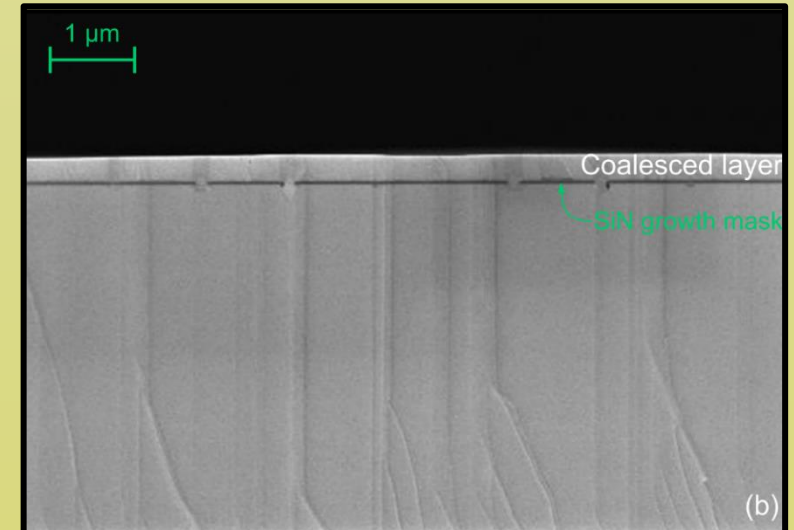
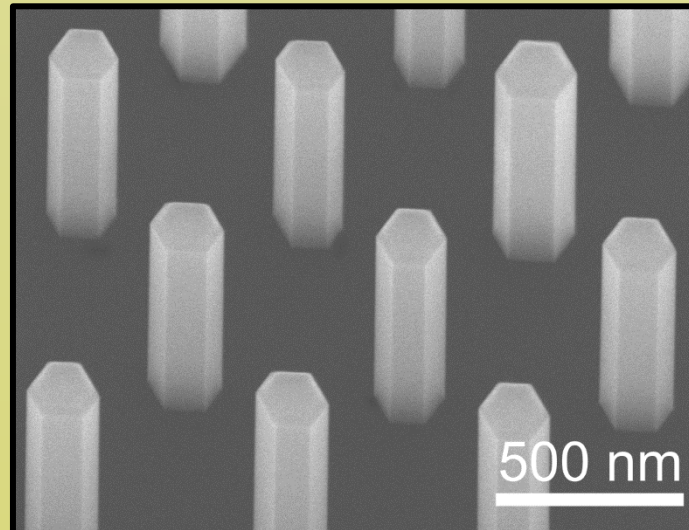
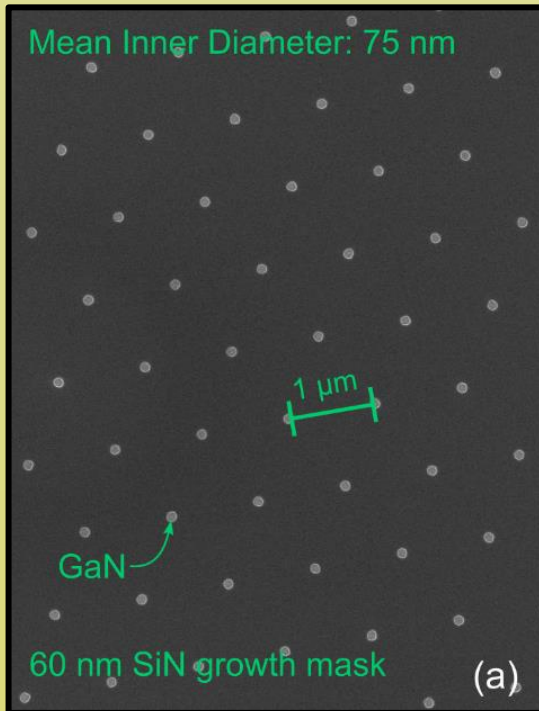
Patterned SiN mask on AlGaN/GaN/Si



GaN nanopillar epitaxy



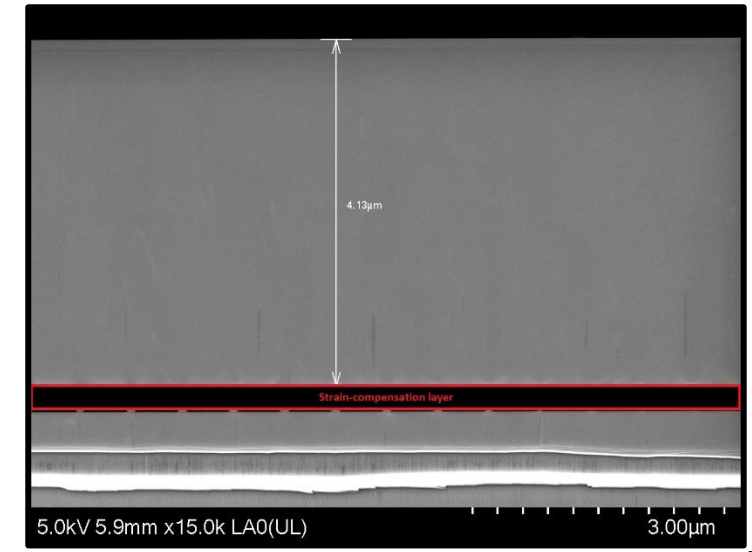
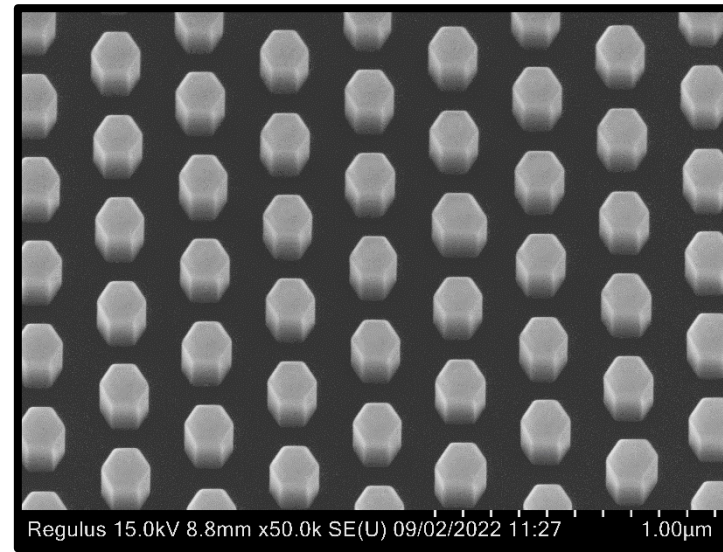
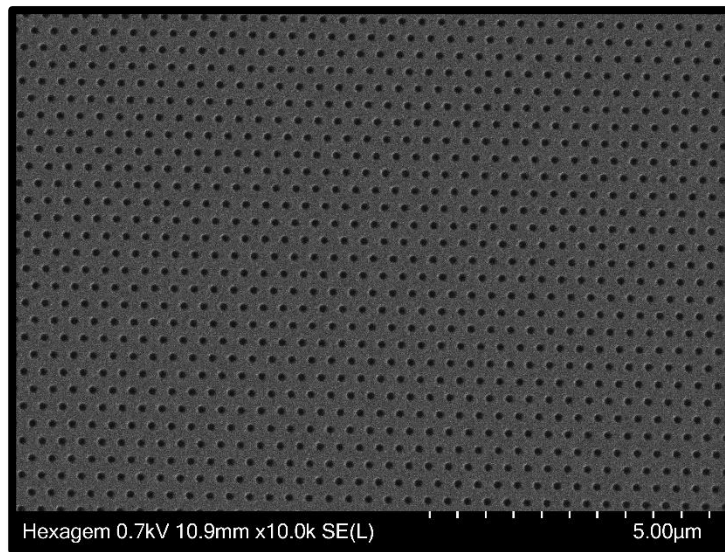
GaN planar layer formation



Novel Nanowire based GaN Epitaxy– UltimateGaN



- Talbot Displacement Lithography – Single exposure, full wafer exposure of < 100 nm regular patterns.
- Nanowire growth for single-crystal seeding of device layers for dislocation filtering.
- Nanowire coalescence allows for thick drift layers, enabling high breakdown voltages for vertical power devices.
- Materials characterization by XRD, AFM, SEM, and EDX.

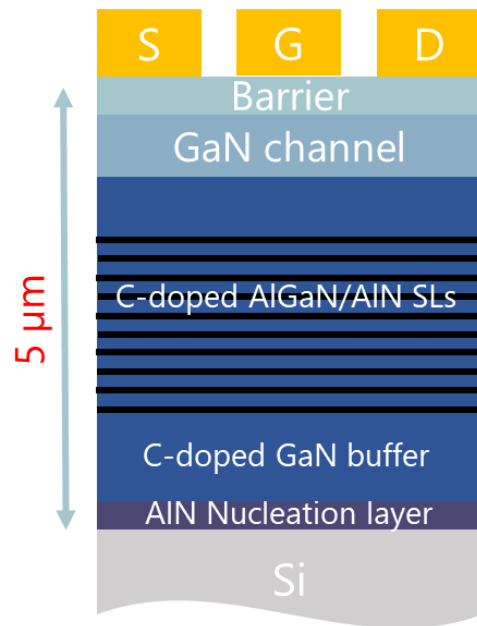


T2.3.2: Cost competitive alternative substrates

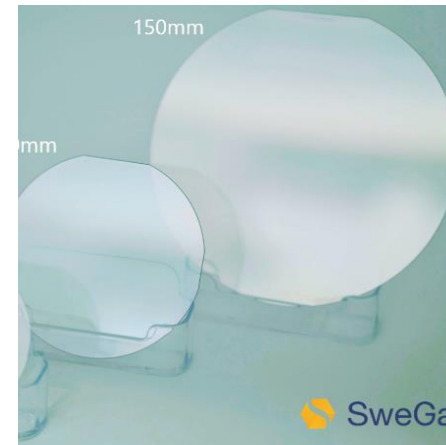
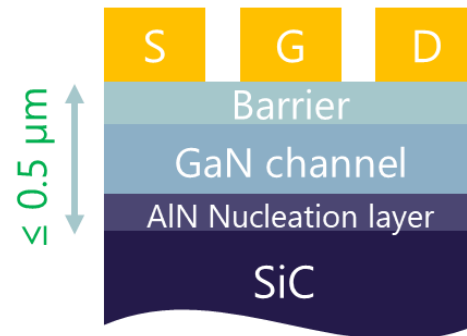
- QuanFINE®, buffer-free GaN-on-SiC epitaxy



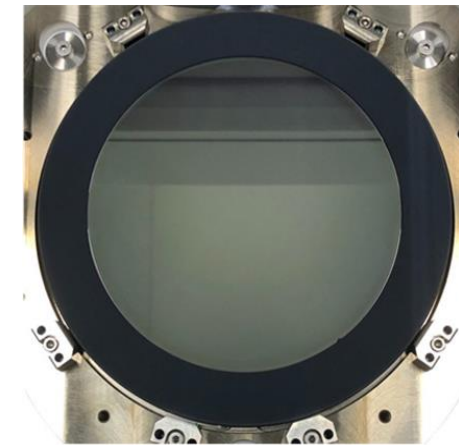
GaN on Si



QuanFINE



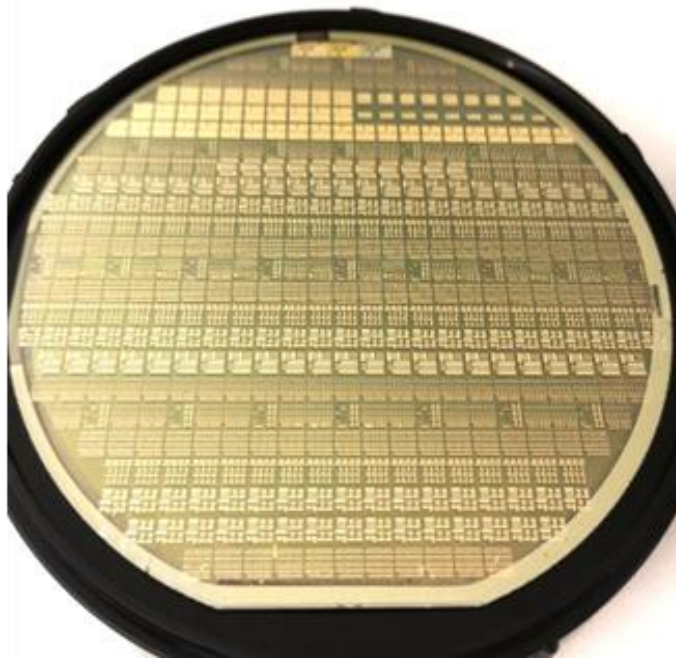
- The buffer-free GaN-on-SiC epitaxy is successfully scaled to 6" and mass produced in a high-throughput reactor.



- The dislocation density in QuanFINE® epiwafers is around mid 10^8 cm^{-2}
- >1000x better than GaN-on-Si for lateral ≤ 600/650V devices in the first 300nm GaN layer.

T2.3.2: Cost competitive alternative substrates

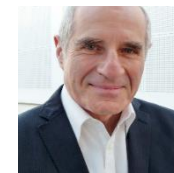
- Power HEMTs based on QuanFINE wafers



- 6" processed QuanFINE epiwafer fabricated by RISE using GaN power HEMT technology developed in UltimateGaN



Michael Salter



Prof. Bakowski



Prof. Q. Wang



- **Benchmarking HEMTs on different substrates**

HEMTs based on QuanFINE (buffer free GaN-on-SiC) and GaN-on-Si substrate were fabricated by the same process run. The QuanFINE epi wafers were more robust during the fabrication, which may enable higher yields.

- **Low gate leakage and high I_{on}/I_{off} ratio**

Low gate leakage in pA scale and I_{on}/I_{off} to 10^{11} were achieved for both material systems. Such the state-of-the-art figure of merit of the devices demonstrates good process control and throughput.

- **High breakdown voltage**

Breakdown electric field performance was verified to be beyond state of the art for the QuanFINE HEMT devices, achieving 1.1 MV/cm with 10 um gate-drain length with low leakage current in nA scale.

- **High output current**

The output current of 27A was demonstrated for a QuanFINE multiple-finger HEMT that assembled in a ceramic packaging with integrated heatsink at RISE.

T4.1.3 Package development for power GaNs

Fully-printed package for power GaNs

- Both dielectric and conducting parts were fabricated using multi-material printing.
- Dielectric ink (DI): polyimide. Conductive ink (CI): silver.
- First characterization results promising.

• Task Lead:	SAL		
• Partner:	RISE		

Commercial Package from GaN Systems

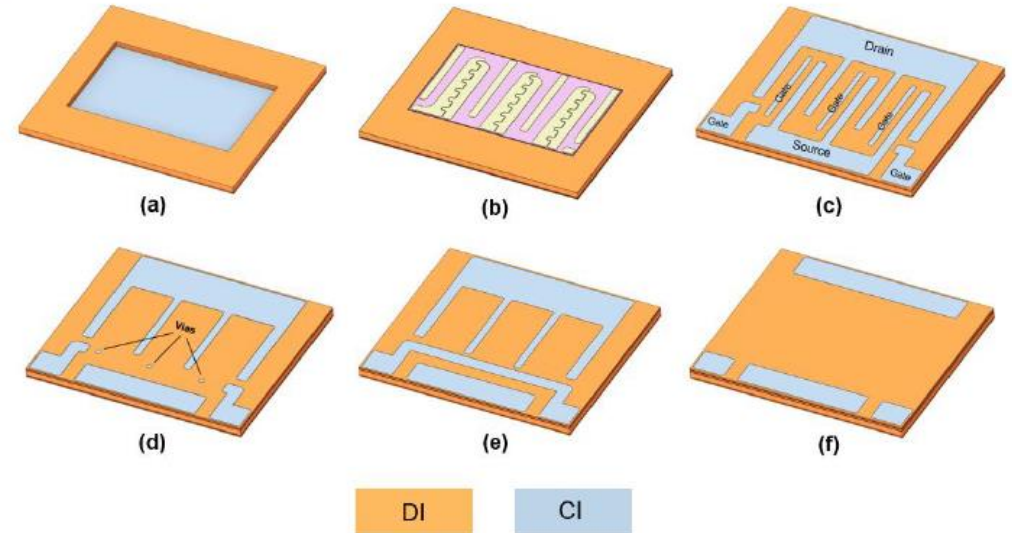
Top Side



Bottom Side



Printed Package



Thank you!

Michael Salter

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